


<b>Search Notes</b> 	<b>Application/Control No.</b> 10590763	<b>Applicant(s)/Patent Under Reexamination</b> CHYUN, CHAN HYUK
	<b>Examiner</b> Darren W Ark	<b>Art Unit</b> 3643

SEARCHED			
Class	Subclass	Date	Examiner
43	114	12/22/2008	DA

SEARCH NOTES		
Search Notes	Date	Examiner
A01M 1/14 (not U.S.)	12/22/2008	DA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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